

# NanoMill® TEM specimen preparation system



### NanoMill<sup>®</sup> TEM specimen preparation system

#### **Main Features:**

- Ultra-low energy ion source
- Concentrated ion beam
- Removes amorphous and implanted layers
- Ideal for post-focused ion beam processing and milling of conventionally prepared specimens
- Liquid nitrogen-cooled specimen stage

## Main Applications:

**TEM Specimen preparation** 





Contact Bernal Institute E: <u>bernal.institute@ul.ie</u>



#### www.bernalinstitute.com